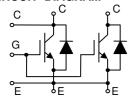
MBN1200E17D

Silicon N-channel IGBT

FEATURES

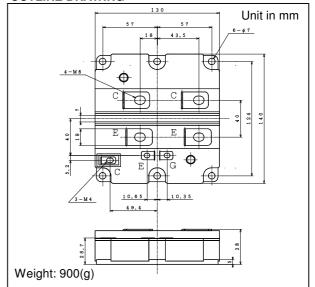
- * High speed, low loss IGBT module.
- * Low driving power due to low input capacitance MOS gate.
- * Low noise due to ultra soft fast recovery diode.
- * High reliability, high durability module.
- * High thermal fatigue durability. (delta Tc=70°C, N>30,000cycles)
- * Isolated heat sink (terminal to base).

CIRCUIT DIAGRAM



ABSOLUTE MAXIMUM RATINGS (Tc=25°C)

OUTLINE DRAWING



| Item | | Symbol | Unit | MBN1200E17D | |
|---------------------------|-------------------|------------------|-----------|--------------------|--|
| Collector Emitter Voltage | | $V_{\sf CES}$ | V | 1,700 | |
| Gate Emitter Voltage | | V_{GES} | V | ±20 | |
| Collector Current | DC | Ιc | Α | 1,200 | |
| Collector Current | 1ms | I _{Cp} | 1 ^ | 2,400 | |
| Forward Current | DC | l _F | Α | 1,200 | |
| Forward Gurrent | 1ms | I _{FM} | A | 2,400 | |
| Junction Temperature | | Ti | °C | -40 ~ +125 | |
| Storage Temperature | | T _{stq} | °C | -40 ~ +125 | |
| Isolation Voltage | | V _{ISO} | V_{RMS} | 4,000(AC 1 minute) | |
| Screw Torque | Terminals (M4/M8) | - | N·m | 2/10 (1) | |
| | Mounting (M6) | - | INTIII | 6 (2) | |

Notes: (1) Recommended Value 1.8±0.2/9±1N·m

(2) Recommended Value 5.5±0.5N·m

ELECTRICAL CHARACTERISTICS

| Item | | Symbol | Unit | Min. | Тур. | Max. | Test Conditions |
|--------------------------------------|---------------|-----------------------|-------|------|-------|-------|--|
| Collector Emitter Cut-Off Current | | I _{CES} | mA | - | - | 10 | V _{CE} =1,700V, V _{GE} =0V, Tj=25°C |
| | | | | - | 10 | 35 | V _{CE} =1,700V, V _{GE} =0V, Tj=125°C |
| Gate Emitter Leakage Current | | I_{GES} | nA | -500 | - | +500 | V _{GE} =±20V, V _{CE} =0V, Tj=25°C |
| Collector Emitter Saturation Voltage | | $V_{CE(sat)}$ | V | 2.0 | 2.7 | 3.3 | I _C =1,200A, V _{GE} =15V, Tj=125°C |
| Gate Emitter Threshold Voltage | | $V_{GE(TO)}$ | V | 5.0 | 6.5 | 8.0 | V _{CE} =10V, I _C =120mA, Tj=25°C |
| Input Capacitance | | Cies | nF | - | 100 | - | V _{CE} =10V, V _{GE} =0V, f=100kHz, Tj=25°C |
| Internal Gate Resistance | | Rge | Ω | - | 0.8 | - | $V_{CE}=10V$, $V_{GE}=0V$, $f=100kHz$, $Tj=25$ °C |
| Switching Times | Rise Time | t _r | μs | - | 0.6 | 1.0 | V _{CC} =900V, Ic=1,200A |
| | Turn On Time | t _{on} | | - | 0.9 | 1.8 | $L=65nH,C_{GE}=120nF(TBD)$ (3) |
| | Fall Time | t _f | | - | 0.3 | 0.7 | $R_G=1.5\Omega(TBD)$ (3) $V_{GE}=\pm15V$, $T_J=125^{\circ}C$ |
| | Turn Off Time | t_{off} | | - | 1.4 | 3.4 | |
| Peak Forward Voltage Drop | | V_{FM} | V | 1.3 | 1.9 | 2.5 | IF=1,200A, V _{GE} =0V, Tj=125°C |
| Reverse Recovery Time | | t _{rr} | μs | - | 0.5 | 1.0 | V _{CC} =900V, Ic=IF=1,200A |
| Turn On Loss | | E _{on(10%)} | J/P | 0.09 | 0.25 | 0.4 | $L=65nH,C_{GE}=120nF(TBD) (3)$ |
| Turn Off Loss | | E _{off(10%)} | J/P | 0.18 | 0.35 | 0.5 | $R_{G}=1.5\Omega(TBD)$ (3) |
| Reverse Recovery Loss | | E _{rr(10%)} | J/P | 0.18 | 0.4 | 0.6 | V _{GE} =±15V, Tj=125°C |
| Stray inductance module | | Lsce | nΗ | - | 18 | - | |
| Thermal Impedance IGBT | | Rth(j-c) | K/W | - | - | 0.018 | Junction to case |
| memai impedance | FWD | Rth(j-c) | 17/77 | - | - | 0.030 | oundion to case |
| Contact Thermal Impedance | | Rth(c-f) | K/W | - | 0.008 | - | Case to fin |

Notes:(3) R_G and C_{GE} value is the test condition's value for evaluation of the switching times, not recommended value. Please, determine the suitable R_G and C_{GE} value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.



MBN1200E17D

DEFINITION OF TEST CIRCUIT

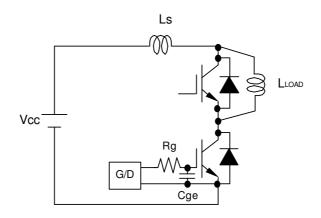


Fig.1 Switching test circuit

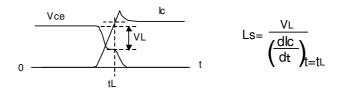


Fig.2 Definition of stray inductance

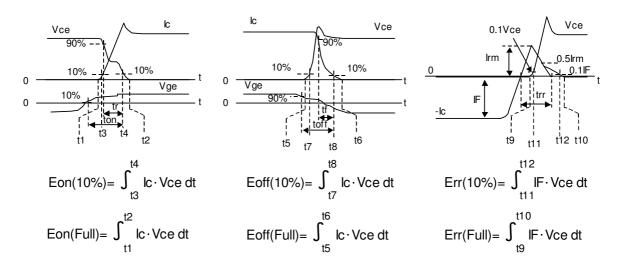
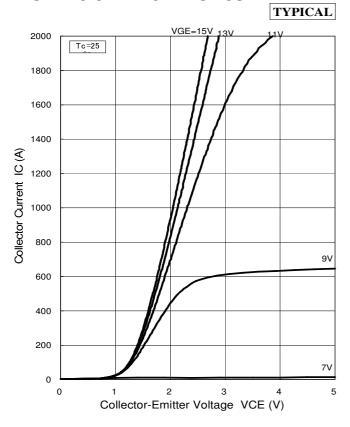
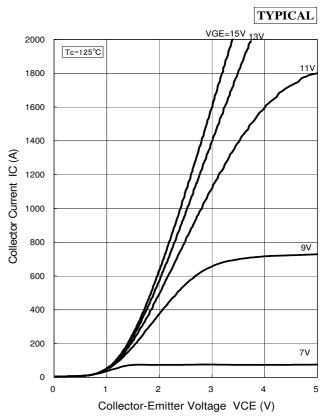


Fig.3 Definition of switching loss

MBN1200E17D

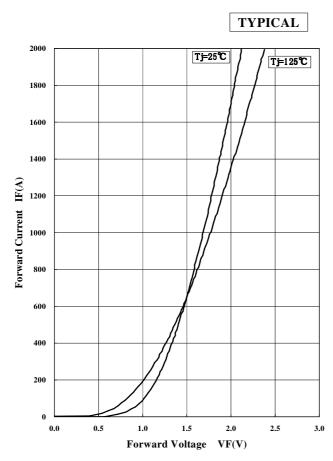
1. STATIC CHARACTERISTICS





Collector Current vs.Collector to Emitter Voltage

Collector Current vs.Collector to Emitter Voltage

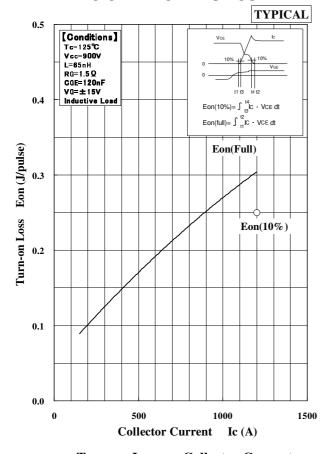


Forward Voltage of free-wheeling diode

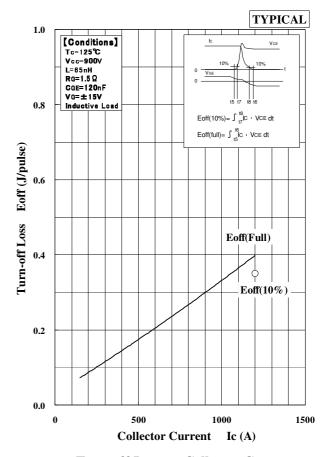


MBN1200E17D

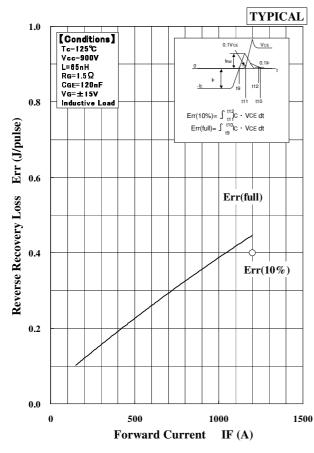
2. DYNAMIC CHARACTERISTICS



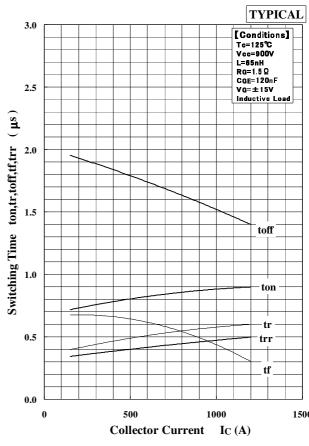
Turn-on Loss vs. Collector Current



Turn-off Loss vs. Collector Current



Recovery Loss vs. Forward Current



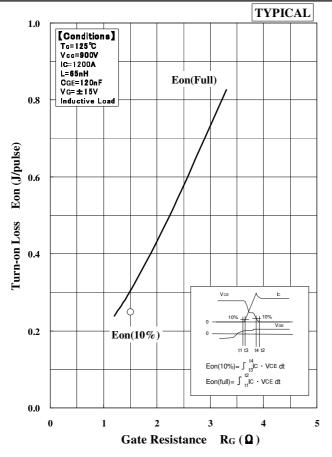
Switching Time vs. Collector Current



Conditions
To=125°C
Voo=900V
IC=1200A
L=65nH
CGE=120nF
VG=±15V
Inductive Load

0.8

MBN1200E17D



Eoff(full) = \(\int_{\text{sign}}^{\text{for VCE dt}} \)

Eoff(Full)

Eoff(Full)

O.2

0.0

1 2 3 4 5

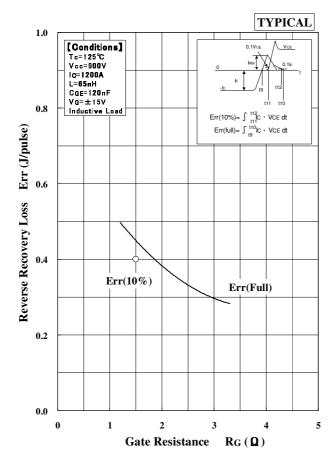
Gate Resistance $R_G(\Omega)$

Turn-off Loss vs. Gate Resistance

TYPICAL

Eoff(10%)= \int_{t7}^{t8} IC · VCE dt

Turn-on Loss vs. Gate Resistance

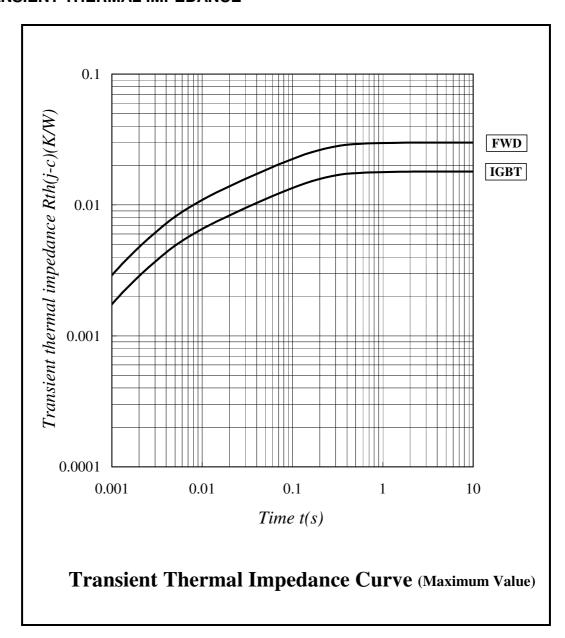


Recovery Loss vs. Gate Resistance



MBN1200E17D

3. TRANSIENT THERMAL IMPEDANCE



4. Negative environmental impact material

Please note that following materials are contained in the product In order to keep characteristics and reliability level.

| Material | Contained part | | |
|-----------------------------|----------------|--|--|
| Lead (Pb) and its compounds | Solder | | |
| Arsenic and its compounds | Si chip | | |



MBN1200E17D

HITACHI POWER SEMICONDUCTORS

Notices

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- 2. Please be sure to read "Precautions for Safe Use and Notices" in the individual brochure before use.
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